

AdAM: Adaptive Approximate Multiplier for Fault Tolerance in DNN Accelerators

Taheri, Mahdi; Cherezova, Natalia; Nazari, Samira; Azarpeyvand, Ali; Ghasempouri, Tara; Daneshtalab, Masoud; Raik, Jaan; Jenihhin, Maksim IEEE transactions on device and materials reliability 2024 / p. 66-75 : ill <https://doi.org/10.1109/TDMR.2024.3523386>

AdAM: adaptive fault-tolerant approximate multiplier for edge DNN accelerators

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